

Search Notes**Application/Control No.**

10/777,026

Examiner

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Applicant(s)/Patent under Reexamination

KAWAGUCHI ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	68	5/9/2006	BT
216	69	5/9/2006	BT
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**SEARCH NOTES
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